

<b>Notice of References Cited</b>	Application/Control No. 10/693,459	Applicant(s)/Patent Under Reexamination KIM ET AL.	
	Examiner Vincent E. Kovalick	Art Unit 2629	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,909,035	06-1999	Kim, Jeom Jae	257/59
*	B	US-5,847,797	12-1998	Van Dijk, Antonius J. M.	349/158
*	C	US-5,838,400	11-1998	Ueda et al.	349/58
*	D	US-5,737,272	04-1998	Uchiyama et al.	345/206
*	E	US-5,701,167	12-1997	Yamazaki, Shunpei	349/42
*	F	US-5,592,199	01-1997	Kawaguchi et al.	345/206
*	G	US-5,565,885	10-1996	Tamanai, Yutaka	345/100
*	H	US-5,523,187	06-1996	Shin, Woo S.	430/20
*	I	US-5,358,412	10-1994	Maurinus et al.	439/66
*	J	US-4,757,235	07-1988	Nunomura et al.	313/509
*	K	US-4,458,987	07-1984	Sasaki et al.	349/79
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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